

AGENDA - Asian IBIS Summit (Tokyo) Monday, November 12, 2018

Akihabara UDX
Tokyo, Japan

Room: **4F NEXT1**

Sponsors: **Japan Electronics and Information Technology Industries Association (JEITA)
IBIS Open Forum**

ANSYS, Inc.
Apollo
Cadence Design Systems
Cybernet Systems
Keysight Technologies
Ricoh
Toshiba Corporation
Zuken, Inc.

(Order and times subject to change)

13:00 **SIGN IN**

13:05 **MEETING WELCOMES**

- Mike LaBONTE (SiSoft, USA)
Chair, IBIS Open Forum
- Miyo KAWATA (ANSYS Japan K.K., Japan)
Chair, JEITA EDA Model Subcommittee

13:10 **JEITA EDA Model Specialty Committee Report**

Miyo KAWATA (ANSYS Japan K.K., Japan)

13:15 **IBIS Update**

Mike LaBONTE (SiSoft, USA)

13:25 **Package Models for Critical Timing Validation with IBIS**

Yukio MASUKO (Japan Electronics Packaging and Circuits Association
(JPCA), Japan)

13:50 **Best Case Analysis**

Shinichi MAEDA (KEI Systems, Japan)

14:15 **A Practical Methodology for SerDes Design**

Amy ZHANG*, Guohua WANG*, David ZHANG*, Zilwan MAHMOD*, Anders EKHOLM**
(Ericsson, *China, **Sweden)

[Presented by Anders EKHOLM (Ericsson, Sweden)]

14:45 **Model Correlation for IBIS-AMI**

Wenyan XIE*, Guohua WANG*, David ZHANG* Anders EKHOLM**
(Ericsson, *China, **Sweden)

[Presented by Anders EKHOLM (Ericsson, Sweden)]

15:20 **BREAK**

- Reconvene at 15:40

15:40 **Concerns when Applying Channel Simulation to DDR Interface**

Masaki KIRINAKA, Akiko TSUKADA (Fujitsu Interconnect Technologies Limited, Japan)

[Presented by Masaki KIRINAKA (Fujitsu Interconnect Technologies Limited, Japan)]

16:05 **Simulation Technology for Memory Designers in DDR4/5**

Satoshi NAKAMIZO (Keysight Technologies, Japan)

16:30 **Study of DDR Asymmetric Rt/Ft in Existing IBIS-AMI Flow**

Wei-kai SHIH*, Wei-hsing HUANG**; SPISim (*Japan, **USA)

[Presented by Wei-kai SHIH (SPISim, Japan)]

16:55 **Study on Potential Feature Additions for Bit-by-bit Simulation Technique to Address the DDR5 Requirements**

Ted MIDO (Synopsys, Japan)

17:25 **CONCLUDING ITEMS**

17:35 **END OF IBIS SUMMIT MEETING**

- Thank you for your participation

